NTS0104-Q100

Dual supply translating transceiver; open drain; auto direction sensing

Rev. 2 — 23 May 2013 Product data sheet

1. General description

The NTS0104-Q100 is a 4-bit, dual supply translating transceiver with auto direction sensing, that enables bidirectional voltage level translation. It features two 4-bit input-output ports (An and Bn), one output enable input (OE) and two supply pins ($V_{CC(A)}$ and $V_{CC(B)}$). $V_{CC(A)}$ can be supplied with any voltage between 1.65 V and 3.6 V. $V_{CC(B)}$ can be supplied with any voltage between 2.3 V and 5.5 V. The range in supply voltages makes the device suitable for translating between any of the voltage nodes (1.8 V, 2.5 V, 3.3 V and 5.0 V). Pins An and OE are referenced to $V_{CC(A)}$ and pins Bn are referenced to $V_{CC(B)}$. A LOW level at pin OE causes the outputs to assume a high-impedance OFF-state. This device is fully specified for partial power-down applications using I_{OFF}. The I_{OFF} circuitry disables the output, preventing the damaging backflow current through the device when it is powered down.

This product has been qualified to the Automotive Electronics Council (AEC) standard Q100 (Grade 1) and is suitable for use in automotive applications.

2. Features and benefits

- Automotive product qualification in accordance with AEC-Q100 (Grade 1)
  - Specified from –40 °C to +85 °C and from –40 °C to +125 °C
- Wide supply voltage range:
  - $V_{CC(A)}$: 1.65 V to 3.6 V and $V_{CC(B)}$: 2.3 V to 5.5 V
- Maximum data rates:
  - Push-pull: 50 Mbps
- I_{OFF} circuitry provides partial Power-down mode operation
- Inputs accept voltages up to 5.5 V
- ESD protection:
  - MIL-STD-883, method 3015 Class 2 exceeds 2500 V for A port
  - MIL-STD-883, method 3015 Class 3B exceeds 15000 V for B port
  - HBM JESD22-A114E Class 2 exceeds 2500 V for A port
  - HBM JESD22-A114E Class 3B exceeds 15000 V for B port
  - MM JESD22-A115-A exceeds 200 V (C = 200 pF, R = 0 Ω)
- Latch-up performance exceeds 100 mA per JESD 78B Class II
- Multiple package options

3. Applications

- I^2C/SMBus
- UART
- GPIO

4. Ordering information

Table 1. Ordering information

Type number	Package			
	Temperature range	Name	Description	Version
NTS0104PW-Q100	−40 °C to +125 °C	TSSOP14	plastic thin shrink small outline package; 14 leads; body width 4.4 mm	SOT402-1
NTS0104BQ-Q100	−40 °C to +125 °C	DHVQFN14	plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 14 terminals; body 2.5 × 3 × 0.85 mm	SOT762-1
NTS0104UK-Q100	−40 °C to +125 °C	WLCSP12	wafer level chip-size package, 12 bumps; body 1.20 × 1.60 × 0.56 mm (Backside Coating included)	NTS0104UK-Q100

5. Marking

Table 2. Marking

Type number	Marking code
NTS0104PW-Q100	NTS0104
NTS0104BQ-Q100	S0104
NTS0104UK-Q100	s04

6. Functional diagram

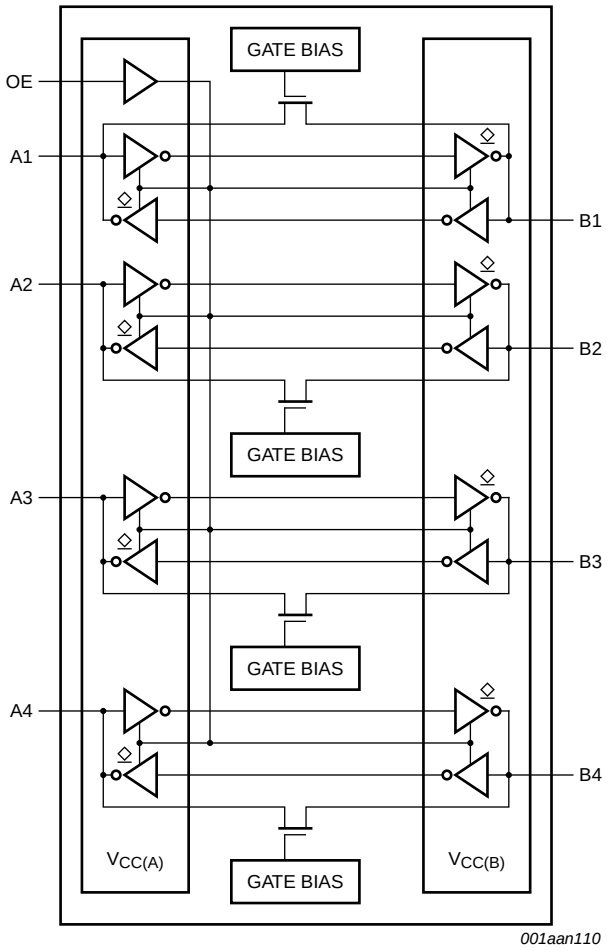


Fig 1. Logic symbol

7. Pinning information

7.1 Pinning

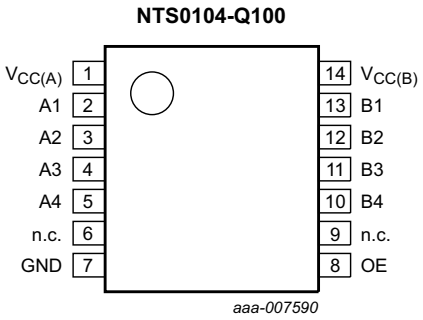
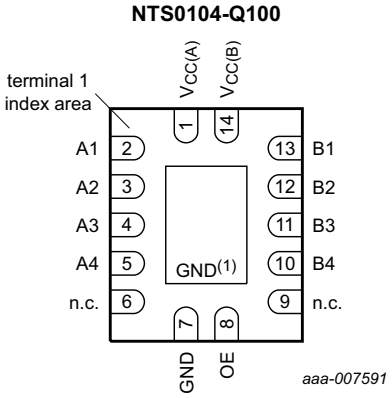


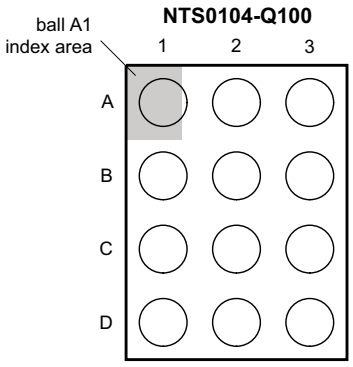
Fig 2. Pin configuration TSSOP14 (SOT402-1)



Transparent top view

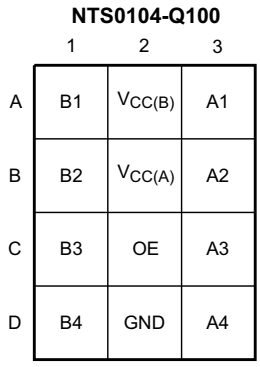
(1) This is not a supply pin, the substrate is attached to this pad using conductive die attach material. There is no electrical or mechanical requirement to solder this pad. However, if it is soldered the solder land should remain floating or connected to GND.

Fig 3. Pin configuration DHVQFN14 (SOT762-1)



Transparent top view

Fig 4. Pin configuration WLCSP12 package



Transparent top view

Fig 5. Ball mapping for WLCSP12

7.2 Pin description

Table 3. Pin description

Symbol	Pin	Ball	Description
	SOT402-1 and SOT762-1	WLCSP12	
$V_{CC(A)}$	1	B2	supply voltage A
A1, A2, A3, A4	2, 3, 4, 5	A3, B3, C3, D3	data input or output (referenced to $V_{CC(A)}$)
n.c.	6, 9	-	not connected
GND	7	D2	ground (0 V)
OE	8	C2	output enable input (active HIGH; referenced to $V_{CC(A)}$)
B4, B3, B2, B1	10, 11, 12, 13	D1, C1, B1, A1	data input or output (referenced to $V_{CC(B)}$)
$V_{CC(B)}$	14	A2	supply voltage B

8. Functional description

Table 4. Function table[1]

Supply voltage		Input	Input/output	
$V_{CC(A)}$	$V_{CC(B)}$	OE	An	Bn
1.65 V to $V_{CC(B)}$	2.3 V to 5.5 V	L	Z	Z
1.65 V to $V_{CC(B)}$	2.3 V to 5.5 V	H	input or output	output or input
GND[2]	GND[2]	X	Z	Z

[1] H = HIGH voltage level; L = LOW voltage level; X = don't care; Z = high-impedance OFF-state.

[2] When either $V_{CC(A)}$ or $V_{CC(B)}$ is at GND level, the device goes into power-down mode.

9. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		Min	Max	Unit
$V_{CC(A)}$	supply voltage A			–0.5	+6.5	V
$V_{CC(B)}$	supply voltage B			–0.5	+6.5	V
V_I	input voltage	A port and OE input	[1][2]	–0.5	+6.5	V
		B port	[1][2]	–0.5	+6.5	V
V_O	output voltage	Active mode	[1][2]			
		A or B port		–0.5	V_{CCO} + 0.5	V
		Power-down or 3-state mode	[1]			
		A port		–0.5	+4.6	V
		B port		–0.5	+6.5	V
I_{IK}	input clamping current	V_I < 0 V		–50	-	mA
I_{OK}	output clamping current	V_O < 0 V		–50	-	mA
I_O	output current	V_O = 0 V to V_{CCO}	[2]	-	±50	mA
I_{CC}	supply current	$I_{CC(A)}$ or $I_{CC(B)}$		-	100	mA
I_{GND}	ground current			–100	-	mA
T_{stg}	storage temperature			–65	+150	°C
P_{tot}	total power dissipation	T_{amb} = −40 °C to +125 °C	[3]	-	250	mW

[1] The minimum input and minimum output voltage ratings may be exceeded if the input and output current ratings are observed.

[2] V_{CCO} is the supply voltage associated with the output.

[3] For TSSOP14 packages: above 60 °C the value of P_{tot} derates linearly at 5.5 mW/K.
For DHVQFN14 packages: above 60 °C the value of P_{tot} derates linearly at 4.5 mW/K.

10. Recommended operating conditions

Table 6. Recommended operating conditions[1][2]

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CC(A)}$	supply voltage A		1.65	3.6	V
$V_{CC(B)}$	supply voltage B		2.3	5.5	V
T_{amb}	ambient temperature		–40	+125	°C
$\Delta t/\Delta V$	input transition rise and fall rate	A or B port; push-pull driving			
		$V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V	-	10	ns/V
		OE input			
		$V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V	-	10	ns/V

[1] Hold the A and B sides of an unused I/O pair in the same state, either both at V_{CCI} or both at GND.

[2] $V_{CC(A)}$ must be less than or equal to $V_{CC(B)}$.

11. Static characteristics

Table 7. Typical static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V); T_{amb} = 25 °C.

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
I_I	input leakage current	OE input; V_I = 0 V to 3.6 V; $V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V		-	-	±1	μA
I_{OZ}	OFF-state output current	A or B port; V_O = 0 V or V_{CCO}; $V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V	[1]	-	-	±1	μA
I_{OFF}	power-off leakage current	A port; V_I or V_O = 0 V to 3.6 V; $V_{CC(A)}$ = 0 V; $V_{CC(B)}$ = 0 V to 5.5 V		-	-	±1	μA
		B port; V_I or V_O = 0 V to 5.5 V; $V_{CC(B)}$ = 0 V; $V_{CC(A)}$ = 0 V to 3.6 V		-	-	±1	μA
C_I	input capacitance	OE input; $V_{CC(A)}$ = 3.3 V; $V_{CC(B)}$ = 3.3 V		-	2	-	pF
$C_{I/O}$	input/output capacitance	A port		-	4	-	pF
		B port		-	7	-	pF
		A or B port; $V_{CC(A)}$ = 3.3 V; $V_{CC(B)}$ = 3.3 V		-	9	-	pF

[1] V_{CCO} is the supply voltage associated with the output.

Table 8. Typical supply current

At recommended operating conditions; voltages are referenced to GND (ground = 0 V); T_{amb} = 25 °C.

$V_{CC(A)}$	$V_{CC(B)}$						Unit
	2.5 V		3.3 V		5.0 V		
	$I_{CC(A)}$	$I_{CC(B)}$	$I_{CC(A)}$	$I_{CC(B)}$	$I_{CC(A)}$	$I_{CC(B)}$	
1.8 V	0.1	0.5	0.1	1.5	0.1	4.6	μA
2.5 V	0.1	0.1	0.1	0.8	0.1	3.8	μA
3.3 V	-	-	0.1	0.1	0.1	2.8	μA

Table 9. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		–40 °C to +85 °C		–40 °C to +125 °C		Unit
				Min	Max	Min	Max	
V_{IH}	HIGH-level input voltage	A port						
		$V_{CC(A)}$ = 1.65 V to 1.95 V; $V_{CC(B)}$ = 2.3 V to 5.5 V	[1]	V_{CCI} – 0.2	-	V_{CCI} – 0.2	-	V
		$V_{CC(A)}$ = 2.3 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V	[1]	V_{CCI} – 0.4	-	V_{CCI} – 0.4	-	V
		B port						
		$V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V	[1]	V_{CCI} – 0.4	-	V_{CCI} – 0.4	-	V
		OE input						
		$V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V		$0.65V_{CC(A)}$	-	$0.65V_{CC(A)}$	-	V

Table 9. Static characteristics *…continued*

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		–40 °C to +85 °C		–40 °C to +125 °C		Unit
				Min	Max	Min	Max	
V_{IL}	LOW-level input voltage	A or B port						
		$V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V		-	0.15	-	0.15	V
		OE input						
		$V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V		-	$0.35V_{CC(A)}$	-	$0.35V_{CC(A)}$	V
V_{OH}	HIGH-level output voltage	A or B port; I_O = –20 μA						
		$V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V	[2]	$0.67V_{CCO}$	-	$0.67V_{CCO}$	-	V
V_{OL}	LOW-level output voltage	A or B port; I_O = 1 mA	[2]					
		$V_I \leq 0.15$ V; $V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V		-	0.4	-	0.4	V
I_I	input leakage current	OE input; V_I = 0 V to 3.6 V; $V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V		-	±2	-	±12	μA
I_{OZ}	OFF-state output current	A or B port; V_O = 0 V or V_{CCO}; $V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V	[2]	-	±2	-	±12	μA
I_{OFF}	power-off leakage current	A port; V_I or V_O = 0 V to 3.6 V; $V_{CC(A)}$ = 0 V; $V_{CC(B)}$ = 0 V to 5.5 V		-	±2	-	±12	μA
		B port; V_I or V_O = 0 V to 3.6 V; $V_{CC(B)}$ = 0 V; $V_{CC(A)}$ = 0 V to 3.6 V		-	±2	-	±12	μA
I_{CC}	supply current	V_I = 0 V or V_{CCI}; I_O = 0 A	[1]					
		$I_{CC(A)}$						
		$V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V		-	2.4	-	15	μA
		$V_{CC(A)}$ = 3.6 V; $V_{CC(B)}$ = 0 V		-	2.2	-	15	μA
		$V_{CC(A)}$ = 0 V; $V_{CC(B)}$ = 5.5 V		-	–1	-	–8	μA
		$I_{CC(B)}$						
		$V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V		-	12	-	30	μA
		$V_{CC(A)}$ = 3.6 V; $V_{CC(B)}$ = 0 V		-	–1	-	–5	μA
		$V_{CC(A)}$ = 0 V; $V_{CC(B)}$ = 5.5 V		-	1	-	6	μA
		$I_{CC(A)} + I_{CC(B)}$						
		$V_{CC(A)}$ = 1.65 V to 3.6 V; $V_{CC(B)}$ = 2.3 V to 5.5 V		-	14.4	-	45	μA

[1] V_{CCI} is the supply voltage associated with the input.

[2] V_{CCO} is the supply voltage associated with the output.

12. Dynamic characteristics

Table 10. Dynamic characteristics for temperature range –40 °C to +85 °C[1]

Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 8; for wave forms see Figure 6 and Figure 7.

Symbol	Parameter	Conditions		$V_{CC(B)}$						Unit
				2.5 V ± 0.2 V		3.3 V ± 0.3 V		5.0 V ± 0.5 V		
				Min	Max	Min	Max	Min	Max	
$V_{CC(A)}$ = 1.8 V ± 0.15 V										
t_{PHL}	HIGH to LOW propagation delay	A to B		-	4.6	-	4.7	-	5.8	ns
t_{PLH}	LOW to HIGH propagation delay	A to B		-	6.8	-	6.8	-	7.0	ns
t_{PHL}	HIGH to LOW propagation delay	B to A		-	4.4	-	4.5	-	4.7	ns
t_{PLH}	LOW to HIGH propagation delay	B to A		-	5.3	-	4.5	-	0.5	ns
t_{en}	enable time	OE to A; B		-	200	-	200	-	200	ns
t_{dis}	disable time	OE to A; no external load	[2]	-	35	-	35	-	35	ns
		OE to B; no external load	[2]	-	35	-	35	-	35	ns
		OE to A		-	230	-	230	-	230	ns
		OE to B		-	200	-	200	-	200	ns
t_{TLH}	LOW to HIGH output transition time	A port		3.2	9.5	2.3	9.3	1.8	7.6	ns
		B port		3.3	10.8	2.7	9.1	2.7	7.6	ns
t_{THL}	HIGH to LOW output transition time	A port		2.0	5.9	1.9	6.0	1.7	13.3	ns
		B port		2.9	7.6	2.8	7.5	2.8	10.0	ns
$t_{sk(o)}$	output skew time	between channels	[3]	-	0.7	-	0.7	-	0.7	ns
t_W	pulse width	data inputs		20	-	20	-	20	-	ns
f_{data}	data rate			-	50	-	50	-	50	Mbps
$V_{CC(A)}$ = 2.5 V ± 0.2 V										
t_{PHL}	HIGH to LOW propagation delay	A to B		-	3.2	-	3.3	-	3.4	ns
t_{PLH}	LOW to HIGH propagation delay	A to B		-	3.5	-	4.1	-	4.4	ns
t_{PHL}	HIGH to LOW propagation delay	B to A		-	3.0	-	3.6	-	4.3	ns
t_{PLH}	LOW to HIGH propagation delay	B to A		-	2.5	-	1.6	-	0.7	ns
t_{en}	enable time	OE to A; B		-	200	-	200	-	200	ns
t_{dis}	disable time	OE to A; no external load	[2]	-	35	-	35	-	35	ns
		OE to B; no external load	[2]	-	35	-	35	-	35	ns
		OE to A		-	200	-	200	-	200	ns
		OE to B		-	200	-	200	-	200	ns
t_{TLH}	LOW to HIGH output transition time	A port		2.8	7.4	2.6	6.6	1.8	6.2	ns
		B port		3.2	8.3	2.9	7.9	2.4	6.8	ns

Table 10. Dynamic characteristics for temperature range –40 °C to +85 °C[1]

Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 8; for wave forms see Figure 6 and Figure 7.

Symbol	Parameter	Conditions		$V_{CC(B)}$						Unit
				2.5 V ± 0.2 V		3.3 V ± 0.3 V		5.0 V ± 0.5 V		
				Min	Max	Min	Max	Min	Max	
t_{THL}	HIGH to LOW output transition time	A port		1.9	5.7	1.9	5.5	1.8	5.3	ns
		B port		2.2	7.8	2.4	6.7	2.6	6.6	ns
$t_{sk(o)}$	output skew time	between channels	[3]	-	0.7	-	0.7	-	0.7	ns
t_W	pulse width	data inputs		20	-	20	-	20	-	ns
f_{data}	data rate			-	50	-	50	-	50	Mbps
$V_{CC(A)}$ = 3.3 V ± 0.3 V										
t_{PHL}	HIGH to LOW propagation delay	A to B		-	-	-	2.4	-	3.1	ns
t_{PLH}	LOW to HIGH propagation delay	A to B		-	-	-	4.2	-	4.4	ns
t_{PHL}	HIGH to LOW propagation delay	B to A		-	-	-	2.5	-	3.3	ns
t_{PLH}	LOW to HIGH propagation delay	B to A		-	-	-	2.5	-	2.6	ns
t_{en}	enable time	OE to A; B		-	-	-	200	-	200	ns
t_{dis}	disable time	OE to A; no external load	[2]	-	-	-	35	-	35	ns
		OE to B; no external load	[2]	-	-	-	35	-	35	ns
		OE to A		-	-	-	260	-	260	ns
		OE to B		-	-	-	200	-	200	ns
t_{TLH}	LOW to HIGH output transition time	A port		-	-	2.3	5.6	1.9	5.9	ns
		B port		-	-	2.5	6.4	2.1	7.4	ns
t_{THL}	HIGH to LOW output transition time	A port		-	-	2.0	5.4	1.9	5.0	ns
		B port		-	-	2.3	7.4	2.4	7.6	ns
$t_{sk(o)}$	output skew time	between channels	[3]	-	-	-	0.7	-	0.7	ns
t_W	pulse width	data inputs		-	-	20	-	20	-	ns
f_{data}	data rate			-	-	-	50	-	50	Mbps

[1] t_{en} is the same as t_{PZL} and t_{PZH}.
t_{dis} is the same as t_{PLZ} and t_{PHZ}.

[2] Delay between OE going LOW and when the outputs are disabled.

[3] Skew between any two outputs of the same package switching in the same direction.

Table 11. Dynamic characteristics for temperature range –40 °C to +125 °C[1]

Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 8; for wave forms see Figure 6 and Figure 7.

Symbol	Parameter	Conditions		$V_{CC(B)}$						Unit
				2.5 V ± 0.2 V		3.3 V ± 0.3 V		5.0 V ± 0.5 V		
				Min	Max	Min	Max	Min	Max	
$V_{CC(A)}$ = 1.8 V ± 0.15 V										
t_{PHL}	HIGH to LOW propagation delay	A to B		-	5.8	-	5.9	-	7.3	ns
t_{PLH}	LOW to HIGH propagation delay	A to B		-	8.5	-	8.5	-	8.8	ns
t_{PHL}	HIGH to LOW propagation delay	B to A		-	5.5	-	5.7	-	5.9	ns
t_{PLH}	LOW to HIGH propagation delay	B to A		-	6.7	-	5.7	-	0.7	ns
t_{en}	enable time	OE to A; B		-	200	-	200	-	200	ns
t_{dis}	disable time	OE to A; no external load	[2]	-	45	-	45	-	45	ns
		OE to B; no external load	[2]	-	45	-	45	-	45	ns
		OE to A		-	250	-	250	-	250	ns
		OE to B		-	220	-	220	-	220	ns
t_{TLH}	LOW to HIGH output transition time	A port		3.2	11.9	2.3	11.7	1.8	9.5	ns
		B port		3.3	13.5	2.7	11.4	2.7	9.5	ns
t_{THL}	HIGH to LOW output transition time	A port		2.0	7.4	1.9	7.5	1.7	16.7	ns
		B port		2.9	9.5	2.8	9.4	2.8	12.5	ns
$t_{sk(o)}$	output skew time	between channels	[3]	-	0.8	-	0.8	-	0.8	ns
t_W	pulse width	data inputs		20	-	20	-	20	-	ns
f_{data}	data rate			-	50	-	50	-	50	Mbps
$V_{CC(A)}$ = 2.5 V ± 0.2 V										
t_{PHL}	HIGH to LOW propagation delay	A to B		-	4.0	-	4.2	-	4.3	ns
t_{PLH}	LOW to HIGH propagation delay	A to B		-	4.4	-	5.2	-	5.5	ns
t_{PHL}	HIGH to LOW propagation delay	B to A		-	3.8	-	4.5	-	5.4	ns
t_{PLH}	LOW to HIGH propagation delay	B to A		-	3.2	-	2.0	-	0.9	ns
t_{en}	enable time	OE to A; B		-	200	-	200	-	200	ns
t_{dis}	disable time	OE to A; no external load	[2]	-	45	-	45	-	45	ns
		OE to B; no external load	[2]	-	45	-	45	-	45	ns
		OE to A		-	220	-	220	-	220	ns
		OE to B		-	220	-	220	-	220	ns
t_{TLH}	LOW to HIGH output transition time	A port		2.8	9.3	2.6	8.3	1.8	7.8	ns
		B port		3.2	10.4	2.9	9.7	2.4	8.3	ns

Table 11. Dynamic characteristics for temperature range –40 °C to +125 °C[1] *…continued*

Voltages are referenced to GND (ground = 0 V); for test circuit see Figure 8; for wave forms see Figure 6 and Figure 7.

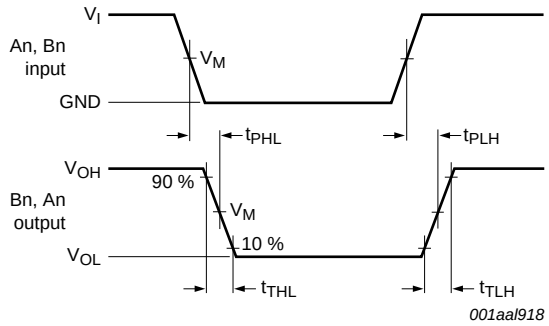
Symbol	Parameter	Conditions		$V_{CC(B)}$						Unit
				2.5 V ± 0.2 V		3.3 V ± 0.3 V		5.0 V ± 0.5 V		
				Min	Max	Min	Max	Min	Max	
t_{THL}	HIGH to LOW output transition time	A port		1.9	7.2	1.9	6.9	1.8	6.7	ns
		B port		2.2	9.8	2.4	8.4	2.6	8.3	ns
$t_{sk(o)}$	output skew time	between channels	[3]	-	0.8	-	0.8	-	0.8	ns
t_W	pulse width	data inputs		20	-	20	-	20	-	ns
f_{data}	data rate			-	50	-	50	-	50	Mbps
$V_{CC(A)}$ = 3.3 V ± 0.3 V										
t_{PHL}	HIGH to LOW propagation delay	A to B		-	-	-	3.0	-	3.9	ns
t_{PLH}	LOW to HIGH propagation delay	A to B		-	-	-	5.3	-	5.5	ns
t_{PHL}	HIGH to LOW propagation delay	B to A		-	-	-	3.2	-	4.2	ns
t_{PLH}	LOW to HIGH propagation delay	B to A		-	-	-	3.2	-	3.3	ns
t_{en}	enable time	OE to A; B		-	-	-	200	-	200	ns
t_{dis}	disable time	OE to A; no external load	[2]	-	-	-	45	-	45	ns
		OE to B; no external load	[2]	-	-	-	45	-	45	ns
		OE to A		-	-	-	280	-	280	ns
		OE to B		-	-	-	220	-	220	ns
t_{TLH}	LOW to HIGH output transition time	A port		-	-	2.3	7.0	1.9	7.4	ns
		B port		-	-	2.5	8.0	2.1	9.3	ns
t_{THL}	HIGH to LOW output transition time	A port		-	-	2.0	6.8	1.9	6.3	ns
		B port		-	-	2.3	9.3	2.4	9.5	ns
$t_{sk(o)}$	output skew time	between channels	[3]	-	-	-	0.8	-	0.8	ns
t_W	pulse width	data inputs		-	-	20	-	20	-	ns
f_{data}	data rate			-	-	-	50	-	50	Mbps

[1] t_{en} is the same as t_{PZL} and t_{PZH}.
t_{dis} is the same as t_{PLZ} and t_{PHZ}.

[2] Delay between OE going LOW and when the outputs are disabled.

[3] Skew between any two outputs of the same package switching in the same direction.

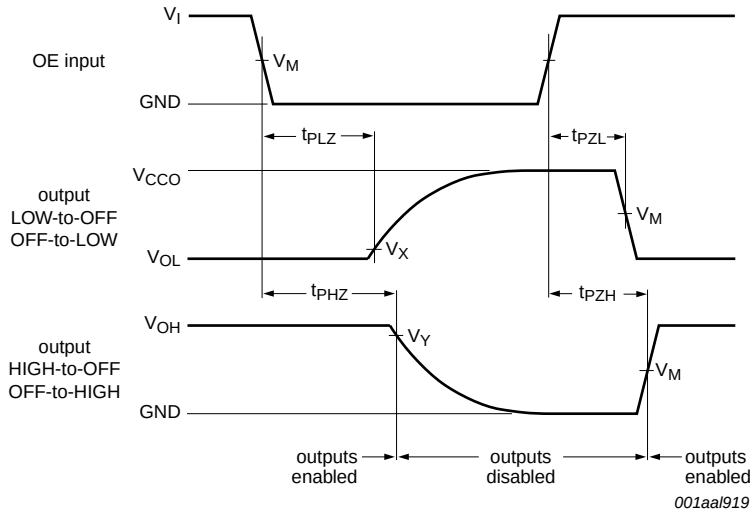
13. Waveforms



Measurement points are given in Table 12.

V_{OL} and V_{OH} are typical output voltage levels that occur with the output load.

Fig 6. The data input (An, Bn) to data output (Bn, An) propagation delay times



Measurement points are given in Table 12.

V_{OL} and V_{OH} are typical output voltage levels that occur with the output load.

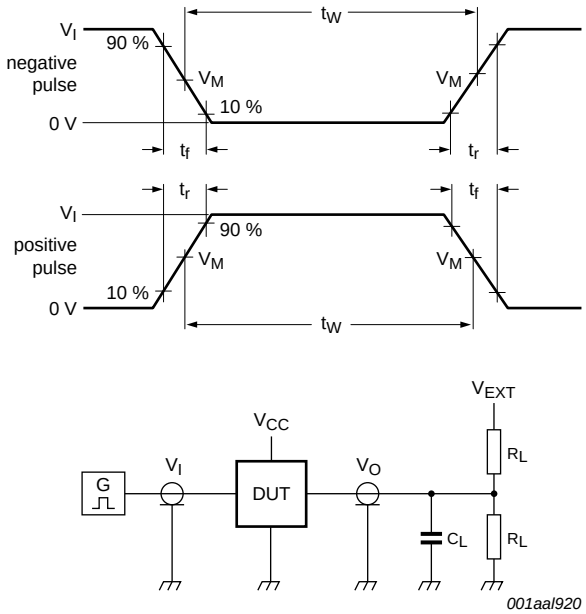
Fig 7. Enable and disable times

Table 12. Measurement points[1][2]

Supply voltage	Input	Output		
V_{CCO}	V_M	V_M	V_X	V_Y
1.8 V ± 0.15 V	$0.5V_{CCI}$	$0.5V_{CCO}$	V_{OL} + 0.15 V	V_{OH} − 0.15 V
2.5 V ± 0.2 V	$0.5V_{CCI}$	$0.5V_{CCO}$	V_{OL} + 0.15 V	V_{OH} − 0.15 V
3.3 V ± 0.3 V	$0.5V_{CCI}$	$0.5V_{CCO}$	V_{OL} + 0.3 V	V_{OH} − 0.3 V
5.0 V ± 0.5 V	$0.5V_{CCI}$	$0.5V_{CCO}$	V_{OL} + 0.3 V	V_{OH} − 0.3 V

[1] V_{CCI} is the supply voltage associated with the input.

[2] V_{CCO} is the supply voltage associated with the output.



Test data is given in Table 13.

All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz; Z_O = 50 Ω; dV/dt ≥ 1.0 V/ns.

R_L = Load resistance.

C_L = Load capacitance including jig and probe capacitance.

V_{EXT} = External voltage for measuring switching times.

Fig 8. Test circuit for measuring switching times

Table 13. Test data

Supply voltage		Input		Load		V_{EXT}		
$V_{CC(A)}$	$V_{CC(B)}$	V_I[1]	Δt/ΔV	C_L	R_L[2]	t_{PLH}, t_{PHL}	t_{PZH}, t_{PHZ}	t_{PZL}, t_{PLZ}[3]
1.65 V to 3.6 V	2.3 V to 5.5 V	V_{CCI}	≤ 1.0 ns/V	15 pF	50 kΩ, 1 MΩ	open	open	$2V_{CCO}$

[1] V_{CCI} is the supply voltage associated with the input.

[2] For measuring data rate, pulse width, propagation delay and output rise and fall measurements, R_L = 1 MΩ. For measuring enable and disable times, R_L = 50 kΩ.

[3] V_{CCO} is the supply voltage associated with the output.

14. Application information

14.1 Applications

Voltage level-translation applications. The NTS0104-Q100 can be used in point-to-point applications to interface between devices or systems operating at different supply voltages. The device is primarily targeted at I^2C or 1-wire which use open-drain drivers. Although it may also be used in applications where push-pull drivers are connected to the ports, the NTB0104-Q100 may be more suitable.

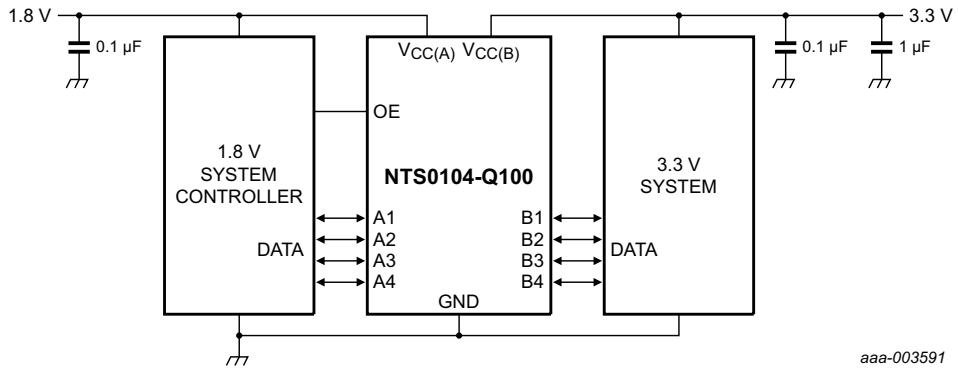


Fig 9. Typical operating circuit

14.2 Architecture

The architecture of the NTS0104-Q100 is shown in Figure 10. The device does not require an extra input signal to control the direction of data flow from A to B or B to A.

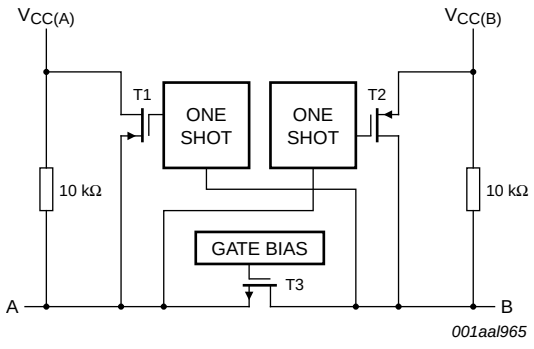


Fig 10. Architecture of NTS0104-Q100 I/O cell (one channel)

The NTS0104-Q100 is a "switch" type voltage translator, it employs two key circuits to enable voltage translation:

1. A pass-gate transistor (N-channel) that ties the ports together.
2. An output edge-rate accelerator that detects and accelerates rising edges on the I/O pins.

The gate bias voltage of the pass gate transistor (T3) is set at approximately one threshold voltage above the V_{CC} level of the low-voltage side. During a LOW-to-HIGH transition, the output one-shot accelerates the output transition. This acceleration is achieved by switching on the PMOS transistors (T1, T2) bypassing the 10 kΩ pull-up resistors and increasing current drive capability. The one-shot is activated once the input transition reaches approximately $V_{CCI}/2$; it is de-activated approximately 50 ns after the output reaches $V_{CCO}/2$. During the acceleration time, the driver output resistance is between approximately 50 Ω and 70 Ω. To avoid signal contention and minimize dynamic I_{CC}, wait for the one-shot circuit to turn-off before applying a signal in the opposite direction. Pull-up resistors are included in the device for DC current sourcing capability.

14.3 Input driver requirements

As the NTS0104-Q100 is a switch type translator, properties of the input driver directly affect the output signal. The external open-drain or push-pull driver applied to an I/O, determines the static current sinking capability of the system. The maximum data rate, HIGH-to-LOW output transition time (t_{THL}) and propagation delay (t_{PHL}), are dependent upon the output impedance and edge-rate of the external driver. The limits provided for these parameters in the data sheet assume a driver with output impedance below 50 Ω is used.

14.4 Output load considerations

The maximum lumped capacitive load that can be driven is dependant upon the one-shot pulse duration. In cases with very heavy capacitive loading, there is a risk that the output does not reach the positive rail within the one-shot pulse duration.

To avoid excessive capacitive loading and to ensure correct triggering of the one-shot, use short trace lengths and low capacitance connectors on NTS0104-Q100 PCB layouts. To ensure low impedance termination and avoid output signal oscillations and one-shot retriggering, control the length of the PCB trace. The PCB trace must limit the round-trip delay of any reflection to within the one-shot pulse duration (approximately 50 ns).

14.5 Power-up

During operation $V_{CC(A)}$ must never be higher than $V_{CC(B)}$. However, during power-up $V_{CC(A)} \geq V_{CC(B)}$ does not damage the device. This means that either power supply can be ramped up first. There is no special power-up sequencing required. The NTS0104-Q100 includes circuitry that disables all output ports when either $V_{CC(A)}$ or $V_{CC(B)}$ is switched off.

14.6 Enable and disable

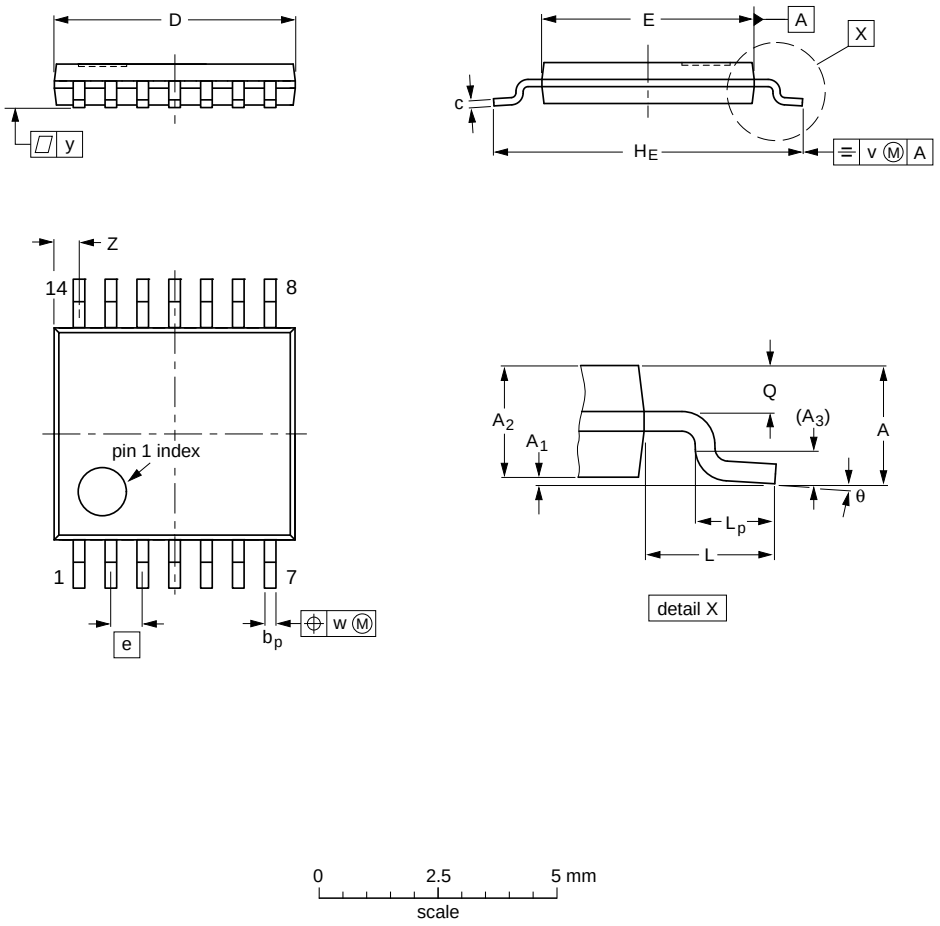
An output enable input (OE) is used to disable the device. Setting OE = LOW causes all I/Os to assume the high-impedance OFF-state. The disable time (t_{dis} with no external load) indicates the delay between when OE goes LOW and when outputs actually become disabled. The enable time (t_{en}) indicates the amount of time required for one one-shot circuit to become operational after OE is taken HIGH. To ensure the high-impedance OFF-state during power-up or power-down, tie pin OE to GND through a pull-down resistor. The current-sourcing capability of the driver determines the minimum value of the resistor.

14.7 Pull-up or pull-down resistors on I/Os lines

Each A port I/O has an internal 10 kΩ pull-up resistor to $V_{CC(A)}$. Each B port I/O has an internal 10 kΩ pull-up resistor to $V_{CC(B)}$. If a smaller value of pull-up resistor is required, add an external resistor in parallel to the internal 10 kΩ. The smaller value, affects the V_{OL} level. When OE goes LOW, the internal pull-ups of the NTS0104-Q100 are disabled.

15. Package outline

TSSOP14: plastic thin shrink small outline package; 14 leads; body width 4.4 mm **SOT402-1**



DIMENSIONS (mm are the original dimensions)

UNIT	A max.	A_1	A_2	A_3	b_p	c	D (1)	E (2)	e	H_E	L	L_p	Q	v	w	y	Z (1)	θ
mm	1.1	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	5.1 4.9	4.5 4.3	0.65	6.6 6.2	1	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.72 0.38	8^o 0^o

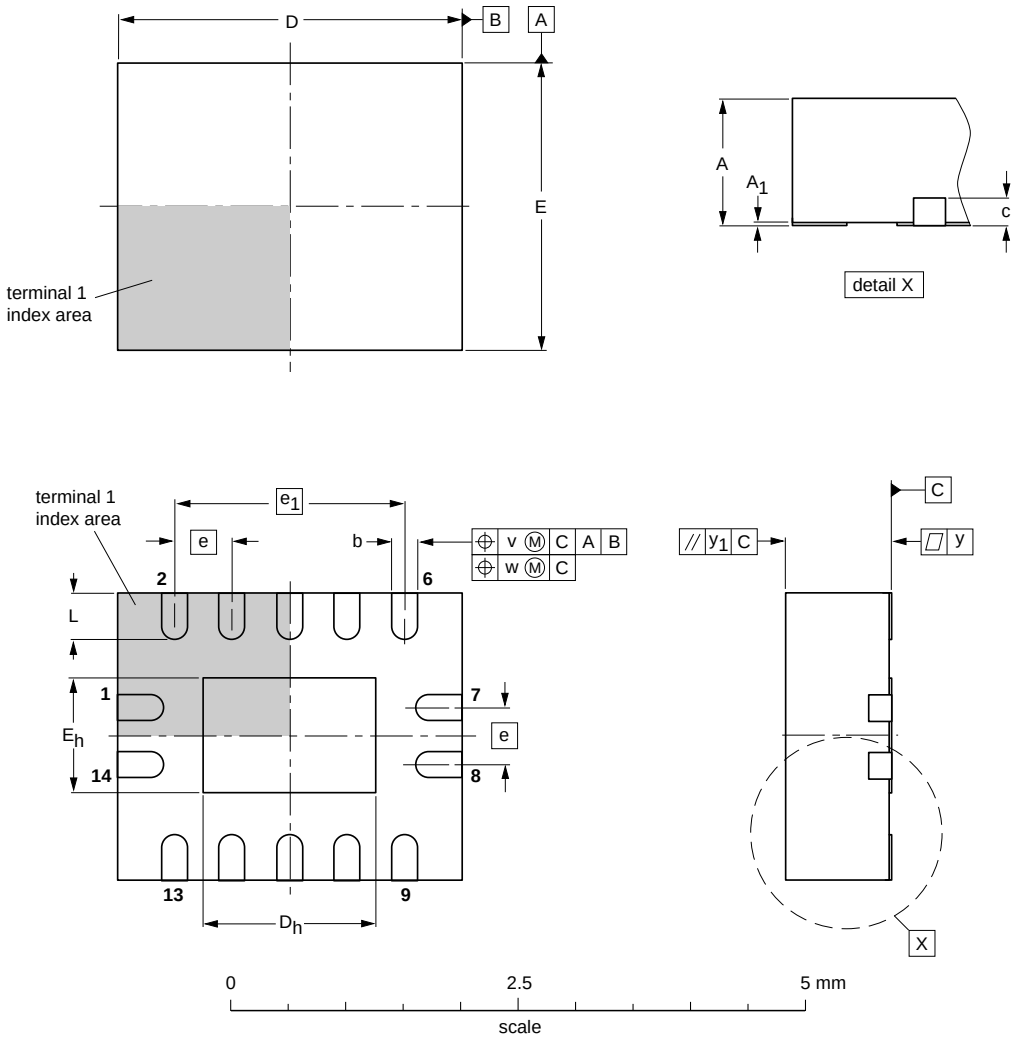
Notes

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT402-1		MO-153				~~99-12-27~~ 03-02-18

Fig 11. Package outline SOT402-1 (TSSOP14)

DHVQFN14: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 14 terminals; body 2.5 x 3 x 0.85 mm **SOT762-1**



DIMENSIONS (mm are the original dimensions)

UNIT	A(1) max.	A_1	b	c	D(1)	D_h	E(1)	E_h	e	e_1	L	v	w	y	y_1
mm	1	0.05 0.00	0.30 0.18	0.2	3.1 2.9	1.65 1.35	2.6 2.4	1.15 0.85	0.5	2	0.5 0.3	0.1	0.05	0.05	0.1

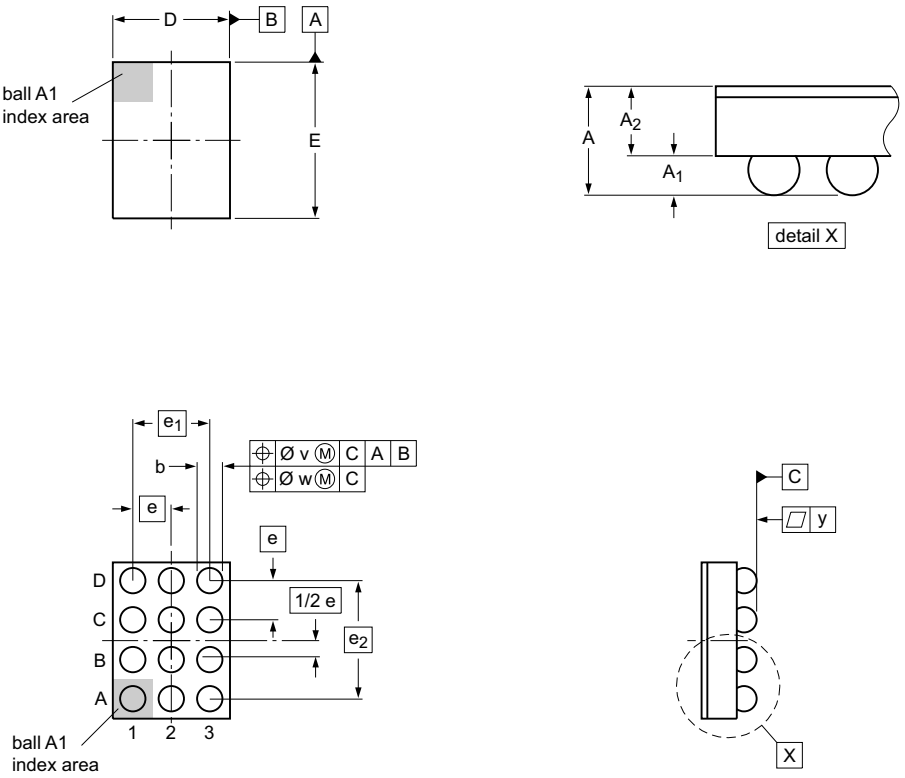
Note

1. Plastic or metal protrusions of 0.075 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT762-1	- - -	MO-241	- - -			~~02-10-17~~ 03-01-27

Fig 12. Package outline SOT762-1 (DHVQFN14)

WLCSP12: wafer level chip-size package,
12 bumps; body 1.20 x 1.60 x 0.56 mm. (Backside Coating included) **NTS0104UK-Q100**



Dimensions

Unit		A	A_1	A_2	b	D	E	e	e_1	e_2	v	w	y
	max	0.615	0.23	0.385	0.29	1.23	1.63						
mm	nom	0.560	0.20	0.360	0.26	1.20	1.60	0.40	0.80	1.20	0.05	0.015	0.03
	min	0.505	0.17	0.335	0.23	1.17	1.57						

nts0104uk-q100_po

Outline version	References				European projection	Issue date
	IEC	JEDEC	JEITA			
NTS0104UK-Q100						~~12-05-21~~ 13-04-23

Fig 13. Package outline WLCSP12 package

16. Abbreviations

Table 14. Abbreviations

Acronym	Description
CDM	Charged Device Model
CMOS	Complementary Metal Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
GPIO	General Purpose Input Output
MIL	Military
HBM	Human Body Model
I^2C	Inter-Integrated Circuit
MM	Machine Model
SMBus	System Management Bus
UART	Universal Asynchronous Receiver Transmitter

17. Revision history

Table 15. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
NTS0104_Q100 v.2	20130523	Product data sheet	-	NTS0104_Q100 v.1
Modifications:	• added type numbers NTS0104PW-Q100 and NTS0104BQ-Q100.			
NTS0104_Q100 v.1	20120807	Product data sheet	-	-

18. Legal information

18.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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